

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHEN ET AL	
		Examiner Van Kim T. Nguyen	Art Unit 2151	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,850,523	02-2005	Karr et al.	370/395.21
	B	US-6,850,526	02-2005	Tan et al.	370/395.6
	C	US-6,816,465	11-2004	Barsoum et al.	370/252
	D	US-6,754,179	06-2004	Lin, Liang-i	370/235
	E	US-6,795,881	09-2004	Bachrach, Yuval	710/100
	F	US-6,671,758	12-2003	Cam et al.	710/100
	G	US-6,421,352	07-2002	Manaka et al.	370/445
	H	US-6,167,029	12-2000	Ramakrishnan, Gopal	370/235
	I	US-6,098,103	08-2000	Dreyer et al.	709/234
	J	US-6,724,725	04-2004	Dreyer et al.	370/231
	K	US-2003/0184458	10-2003	Calvignac et al.	341/102
	L	US-2002/0126704	09-2002	Cam et al.	370/503
	M	US-2002/0122386	09-2002	Calvignac et al.	370/230

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.